GTL2014 4-bit LVTTL to GTL transceiver Rev. 01 — 19 May 2005

**Product data sheet** 

### 1. General description

The GTL2014 is a 4-bit translating transceiver designed for 3.3 V LVTTL system interface with a GTL–/GTL/GTL+ bus.

The direction pin allows the part to function as either a GTL to LVTTL sampling receiver or as a LVTTL to GTL interface.

The GTL2014 LVTTL inputs (only) are tolerant up to 5.5 V allowing direct access to TTL or 5 V CMOS inputs. The LVTTL outputs are not 5.5 V tolerant.

The GTL2014 GTL inputs and outputs operate up to 3.6 V, allowing the device to be used in higher voltage open-drain output applications.

### 2. Features

- Operates as a 4-bit GTL-/GTL/GTL+ sampling receiver or as a LVTTL to GTL-/GTL/GTL+ driver
- 3.0 V to 3.6 V operation with 5 V tolerant LVTTL input
- GTL input and output 3.6 V tolerant
- V<sub>ref</sub> adjustable from 0.5 V to V<sub>CC</sub>/2
- Partial power-down permitted
- ESD protection exceeds 2000 V HBM per JESD22-A114, 200 V MM per JESD22-A115, and 1000 V CDM per JESD22-CC101
- Latch-up protection exceeds 500 mA per JESD78
- Package offered: TSSOP14

### 3. Quick reference data

#### Table 1: Quick reference data

 $T_{amb} = 25 \circ C$ 

Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
t <sub>PLH</sub>	propagation delay; An-to-Bn	$C_L$ = 50 pF; $V_{CC}$ = 3.3 V	-	2.8	-	ns
t <sub>PHL</sub>			-	3.4	-	ns
t <sub>PLH</sub>	propagation delay; Bn-to-An	$C_L = 50 \text{ pF}; V_{CC} = 3.3 \text{ V}$	-	5.2	-	ns
t <sub>PHL</sub>			-	4.9	-	ns
C <sub>i</sub>	input capacitance on pin DIR; A-to-B or B-to-A	$V_I = 0 V \text{ or } V_{CC}$	-	2	2.5	pF
C <sub>io</sub>	input/output capacitance; A-to-B	outputs disabled;	-	4.6	6.0	pF
	input/output capacitance; B-to-A	$V_{I}$ and $V_{O}$ = 0 V or 3.0 V	-	3.4	4.3	pF



## 4. Ordering information

Table 2: Ordering information					
Type number Package					
	Name	Description	Version		
GTL2014PW	TSSOP14	plastic thin shrink small outline package; 14 leads; body width 4.4 mm	SOT402-1		

Standard packing quantities and other packaging data are available at *www.standardics.philips.com/packaging*.

### 4.1 Ordering options

#### Table 3: Ordering options

Type number	Topside mark	Temperature range
GTL2014PW	GTL2014	$T_{amb} = -40 \ ^{\circ}C \ to \ +85 \ ^{\circ}C$

## 5. Functional diagram



## 6. Pinning information

#### 6.1 Pinning



### 6.2 Pin description

Table 4:	Pin description		
Symbol	Pin	Description	
DIR	1	direction control input (LVTTL)	
B0	2	data inputs/outputs (GTL)	
B1	3		
B2	5		
B3	6		
A0	13	data inputs/outputs (LVTTL)	
A1	12		
A2	10		
A3	9		
VREF	4	GTL reference voltage	
GND	7, 8, 11	ground (0 V)	
V <sub>CC</sub>	14	positive supply voltage	

### 7. Functional description

Refer to Figure 1 "Logic diagram for GTL2014" on page 2.

### 7.1 Function table

Table 5:Function table

H = HIGH voltage level; L = LOW voltage level.

Input	Input/output	
DIR	A (LVTTL)	B (GTL)
Н	input	Bn = An
L	An = Bn	input

### 8. Limiting values

#### Table 6: Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). [1] Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC</sub>	DC supply voltage		-0.5	+4.6	V
I <sub>IK</sub>	input clamping diode current	V <sub>I</sub> < 0 V	-	-50	mA
VI	DC input voltage	A port	-0.5[2]	+7.0	V
		B port	-0.5[2]	+4.6	V
Ι <sub>ΟΚ</sub>	output diode clamping current	A port; $V_0 < 0 V$	-	-50	mA
Vo	DC output voltage	output in OFF or HIGH state; A port	-0.5[2]	+7.0	V
		output in OFF or HIGH state; B port	-0.5 [2]	+4.6	V
I <sub>OL</sub>	current into any output in	A port	-	32	mA
	the LOW state	B port	-	80	mA
I <sub>OH</sub>	current into any output in the HIGH state	A port	-	-32	mA
T <sub>stg</sub>	storage temperature range		<u>[3]</u> –60	+150	°C

[1] Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under <u>Section 9 "Recommended operating conditions"</u> is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

[2] The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

[3] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.

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## 9. Recommended operating conditions

Table 7:	Operating condi	tions [ <u>1]</u>				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>CC</sub>	supply voltage		3.0	-	3.6	V
	termination	GTL-	0.85	0.9	0.95	V
	voltage <sup>[2]</sup>	GTL	1.14	1.2	1.26	V
		GTL+	1.35	1.5	1.65	V
V <sub>ref</sub>	reference voltage	overall	0.5	$^{2}$ / $_{3}V_{TT}$	V <sub>CC</sub> /2	V
		GTL-	0.5	0.6	0.63	V
		GTL	0.76	0.8	0.84	V
		GTL+	0.87	1.0	1.10	V
VI	input voltage	B port	0	V <sub>TT</sub>	3.6	V
		except B port	0	3.3	5.5 <mark>3</mark>	V
V <sub>IH</sub>	HIGH-level input voltage	B port	V <sub>ref</sub> + 0.050	-	-	V
		except B port	2	-	-	V
V <sub>IL</sub>	LOW-level input	B port	-	-	$V_{\text{ref}}-0.050$	V
	voltage	except B port	-	-	0.8	V
I <sub>OH</sub>	HIGH-level output current	A port	-	-	-16	mA
I <sub>OL</sub>	LOW-level output	B port	-	-	40	mA
	current	A port	-	-	16	mA
T <sub>amb</sub>	operating ambient temperature	in free-air	-40	-	+85	°C

[1] Unused inputs must be held HIGH or LOW to prevent them from floating.

[2]  $V_{TT}$  maximum of 3.6 V with resistor sized so I<sub>OL</sub> maximum is not exceeded.

[3] A0, A1, A2, A3  $V_{I(max)}$  is 3.6 V if configured as outputs (DIR = L).

### **10. Static characteristics**

#### Table 8: Static characteristics

Recommended operating conditions; voltages are referenced to GND (ground = 0 V).  $T_{amb} = -40 \degree C$  to +85  $\degree C$ 

Symbol	Parameter	Conditions	Min	Typ <mark>[1]</mark>	Max	Unit
V <sub>OH</sub>	HIGH-level output	A port; V_{CC} = 3.0 V to 3.6 V; I_{OH} = -100 $\mu A$	[2] V <sub>CC</sub> – 0.2	-	-	V
voltage	A port; $V_{CC}$ = 3.0 V; $I_{OH}$ = -16 mA	2 2.0	-	-	V	
V <sub>OL</sub>	LOW-level output	B port; $V_{CC}$ = 3.0 V; $I_{OL}$ = 40 mA	[2] _	0.23	0.4	V
	voltage	A port; $V_{CC}$ = 3.0 V; $I_{OL}$ = 8 mA	[2] _	0.28	0.4	V
		A port; $V_{CC} = 3.0 \text{ V}$ ; $I_{OL} = 12 \text{ mA}$	[2] _	0.40	0.55	V
		A port; $V_{CC}$ = 3.0 V; $I_{OL}$ = 16 mA	[2] _	0.55	0.8	V
lı	input current	control inputs; $V_{CC} = 3.6 V$ ; $V_I = V_{CC}$ or GND	-	-	±1	μA
		B port; $V_{CC}$ = 3.6 V; $V_I$ = $V_{TT}$ or GND	-	-	±1	μA
		A port; $V_{CC} = 0$ V or 3.6 V; $V_I = 5.5$ V	-	-	10	μA
		A port; $V_{CC}$ = 3.6 V; $V_I$ = $V_{CC}$	-	-	±1	μA
		A port; $V_{CC} = 3.6 \text{ V}; V_I = 0 \text{ V}$	-	-	-5	μA
I <sub>OZ</sub>	off-state output current	A port; $V_{CC} = 0$ V; $V_I$ or $V_O = 0$ V to 3.6 V	-	-	±100	μA
I <sub>CC</sub>	quiescent supply current	A port; $V_{CC}$ = 3.6 V; $V_I$ = $V_{CC}$ or GND; $I_O$ = 0 mA	-	4	10	mA
		B port; $V_{CC}$ = 3.6 V; $V_I$ = $V_{TT}$ or GND; $I_O$ = 0 mA	-	4	10	mA
$\Delta I_{CC}$ [3]	additional quiescent current (per input)	A port or control inputs; $V_{CC} = 3.6 \text{ V}$ ; V <sub>I</sub> = V <sub>CC</sub> - 0.6 V	-	-	500	μA
Ci	input capacitance	control inputs; $V_I = 3.0$ V or 0 V	-	2	2.5	pF
Cio	input/output	A port; $V_0 = 3.0$ V or 0 V	-	4.6	6	pF
	capacitance	B port; $V_0 = V_{TT}$ or 0 V	-	3.4	4.3	pF

[1] All typical values are measured at V\_{CC} = 3.3 V and T\_{amb} = 25 °C.

[2] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[3] This is the increase in supply current for each input that is at the specified TTL voltage level rather than V<sub>CC</sub> or GND.

## **11. Dynamic characteristics**

#### Table 9: Dynamic characteristics

 $V_{CC} = 3.3 \ V \pm 0.3 \ V$ 

			- 141		11.14
Parameter	Conditions	Min	Typ <mark>[1]</mark>	Max	Unit
0.6 V; V <sub>TT</sub> = 0.9 V					
propagation delay, An to Bn	see Figure 3	-	2.8	5	ns
		-	3.3	7	ns
propagation delay, Bn to An	see Figure 4	-	5.3	8	ns
		-	5.2	8	ns
0.8 V; V <sub>TT</sub> = 1.2 V					
propagation delay, An to Bn	see Figure 3	-	2.8	5	ns
		-	3.4	7	ns
propagation delay, Bn to An	see Figure 4	-	5.2	8	ns
		-	4.9	7	ns
1.0 V; V <sub>TT</sub> = 1.5 V					
propagation delay, An to Bn	see Figure 3	-	2.8	5	ns
		-	3.4	7	ns
propagation delay, Bn to An	see Figure 4	-	5.1	8	ns
		-	4.7	7	ns
	<b>0.6 V; <math>V_{TT} = 0.9 V</math></b> propagation delay, An to Bn propagation delay, Bn to An <b>0.8 V; <math>V_{TT} = 1.2 V</math></b> propagation delay, An to Bn propagation delay, Bn to An <b>1.0 V; <math>V_{TT} = 1.5 V</math> propagation delay, An to Bn</b>	<b>0.6 V; <math>V_{TT} = 0.9 V</math></b> propagation delay, An to Bnsee Figure 3propagation delay, Bn to Ansee Figure 4 <b>0.8 V; <math>V_{TT} = 1.2 V</math></b> propagation delay, An to Bnsee Figure 3propagation delay, Bn to Ansee Figure 4 <b>1.0 V; <math>V_{TT} = 1.5 V</math> propagation delay, An to Bnsee Figure 3</b>	0.6 V; V <sub>TT</sub> = 0.9 V         propagation delay, An to Bn       see Figure 3         propagation delay, Bn to An       see Figure 4         -       -         .0.8 V; V <sub>TT</sub> = 1.2 V       -         propagation delay, An to Bn       see Figure 3         -       -         .0.8 V; V <sub>TT</sub> = 1.2 V       -         propagation delay, An to Bn       see Figure 3         -       -         .0.8 V; V <sub>TT</sub> = 1.5 V       -         propagation delay, An to Bn       see Figure 3         -       -         .10 V; V <sub>TT</sub> = 1.5 V       -         propagation delay, An to Bn       see Figure 3         -       -         .10 V; V <sub>TT</sub> = 1.5 V       -         propagation delay, An to Bn       see Figure 4         -       -         .10 V; V <sub>TT</sub> = 1.5 V       -         .10 V; V <sub>T</sub> = 1.5 V       -         .10 V; V <sub>T</sub> = 1.5 V       -         .10 V; V <sub>T</sub> = 1.5 V       -         .10	0.6 V; $V_{TT} = 0.9 V$ propagation delay, An to Bnsee Figure 3-2.8-3.3-3.3propagation delay, Bn to Ansee Figure 4-5.3-5.2-5.2 <b>D.8 V; V</b> <sub>TT</sub> = 1.2 V5.2propagation delay, An to Bnsee Figure 3-2.8-3.4-5.2propagation delay, Bn to Ansee Figure 4-5.21.0 V; V <sub>TT</sub> = 1.5 V4.9propagation delay, An to Bnsee Figure 3-2.8-3.4-3.4propagation delay, An to Bnsee Figure 3-2.8-3.4-5.1	0.6 V; $V_{TT} = 0.9 V$ propagation delay, An to Bnsee Figure 3-2.85-3.37propagation delay, Bn to Ansee Figure 4-5.38-5.28 <b>D.8 V; V_{TT} = 1.2 V</b> 2.85propagation delay, An to Bnsee Figure 3-2.85-3.47-3.47propagation delay, Bn to Ansee Figure 4-5.28-1.0 V; $V_{TT} = 1.5 V$ -4.97propagation delay, An to Bnsee Figure 3-2.85-3.47-3.47propagation delay, An to Bnsee Figure 4-2.85-3.47-3.47propagation delay, Bn to Ansee Figure 4-5.18

[1] All typical values are at V\_{CC} = 3.3 V and T\_{amb} = 25 °C.

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#### 11.1 Waveforms

 $V_M$  = 1.5 V at  $V_{CC}$   $\geq$  3.0 V;  $V_M$  =  $V_{CC}/2$  at  $V_{CC}$   $\leq$  2.7 V for A ports and control pins;  $V_M$  =  $V_{ref}$  for B ports.



## 12. Test information





R<sub>L</sub> — Load resistor

 $C_L$  — Load capacitance; includes jig and probe capacitance

R<sub>T</sub> — Termination resistance; should be equal to output impedance of pulse generators.

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### 13. Package outline



#### Fig 7. Package outline SOT402-1 (TSSOP14)

### 14. Soldering

#### 14.1 Introduction to soldering surface mount packages

This text gives a very brief insight to a complex technology. A more in-depth account of soldering ICs can be found in our *Data Handbook IC26; Integrated Circuit Packages* (document order number 9398 652 90011).

There is no soldering method that is ideal for all surface mount IC packages. Wave soldering can still be used for certain surface mount ICs, but it is not suitable for fine pitch SMDs. In these situations reflow soldering is recommended.

#### 14.2 Reflow soldering

Reflow soldering requires solder paste (a suspension of fine solder particles, flux and binding agent) to be applied to the printed-circuit board by screen printing, stencilling or pressure-syringe dispensing before package placement. Driven by legislation and environmental forces the worldwide use of lead-free solder pastes is increasing.

Several methods exist for reflowing; for example, convection or convection/infrared heating in a conveyor type oven. Throughput times (preheating, soldering and cooling) vary between 100 seconds and 200 seconds depending on heating method.

Typical reflow peak temperatures range from 215 °C to 270 °C depending on solder paste material. The top-surface temperature of the packages should preferably be kept:

- below 225 °C (SnPb process) or below 245 °C (Pb-free process)
  - for all BGA, HTSSON..T and SSOP..T packages
  - for packages with a thickness  $\geq$  2.5 mm
  - for packages with a thickness < 2.5 mm and a volume ≥ 350 mm<sup>3</sup> so called thick/large packages.
- below 240 °C (SnPb process) or below 260 °C (Pb-free process) for packages with a thickness < 2.5 mm and a volume < 350 mm<sup>3</sup> so called small/thin packages.

Moisture sensitivity precautions, as indicated on packing, must be respected at all times.

#### 14.3 Wave soldering

Conventional single wave soldering is not recommended for surface mount devices (SMDs) or printed-circuit boards with a high component density, as solder bridging and non-wetting can present major problems.

To overcome these problems the double-wave soldering method was specifically developed.

If wave soldering is used the following conditions must be observed for optimal results:

- Use a double-wave soldering method comprising a turbulent wave with high upward pressure followed by a smooth laminar wave.
- For packages with leads on two sides and a pitch (e):
  - larger than or equal to 1.27 mm, the footprint longitudinal axis is preferred to be parallel to the transport direction of the printed-circuit board;

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 smaller than 1.27 mm, the footprint longitudinal axis must be parallel to the transport direction of the printed-circuit board.

The footprint must incorporate solder thieves at the downstream end.

• For packages with leads on four sides, the footprint must be placed at a 45° angle to the transport direction of the printed-circuit board. The footprint must incorporate solder thieves downstream and at the side corners.

During placement and before soldering, the package must be fixed with a droplet of adhesive. The adhesive can be applied by screen printing, pin transfer or syringe dispensing. The package can be soldered after the adhesive is cured.

Typical dwell time of the leads in the wave ranges from 3 seconds to 4 seconds at 250 °C or 265 °C, depending on solder material applied, SnPb or Pb-free respectively.

A mildly-activated flux will eliminate the need for removal of corrosive residues in most applications.

#### 14.4 Manual soldering

Fix the component by first soldering two diagonally-opposite end leads. Use a low voltage (24 V or less) soldering iron applied to the flat part of the lead. Contact time must be limited to 10 seconds at up to 300  $^{\circ}$ C.

When using a dedicated tool, all other leads can be soldered in one operation within 2 seconds to 5 seconds between 270  $^{\circ}$ C and 320  $^{\circ}$ C.

#### 14.5 Package related soldering information

Table 10:	Suitability of surface mount IC	packages for wave and reflow soldering methods

Package [1]	Soldering method		
	Wave	Reflow <sup>[2]</sup>	
BGA, HTSSONT <sup>[3]</sup> , LBGA, LFBGA, SQFP, SSOPT <sup>[3]</sup> , TFBGA, VFBGA, XSON	not suitable	suitable	
DHVQFN, HBCC, HBGA, HLQFP, HSO, HSOP, HSQFP, HSSON, HTQFP, HTSSOP, HVQFN, HVSON, SMS	not suitable <sup>[4]</sup>	suitable	
PLCC <sup>[5]</sup> , SO, SOJ	suitable	suitable	
LQFP, QFP, TQFP	not recommended [5] [6]	suitable	
SSOP, TSSOP, VSO, VSSOP	not recommended [7]	suitable	
CWQCCNL <sup>[8]</sup> , PMFP <sup>[9]</sup> , WQCCNL <sup>[8]</sup>	not suitable	not suitable	

 For more detailed information on the BGA packages refer to the (LF)BGA Application Note (AN01026); order a copy from your Philips Semiconductors sales office.

- [2] All surface mount (SMD) packages are moisture sensitive. Depending upon the moisture content, the maximum temperature (with respect to time) and body size of the package, there is a risk that internal or external package cracks may occur due to vaporization of the moisture in them (the so called popcorn effect). For details, refer to the Drypack information in the Data Handbook IC26; Integrated Circuit Packages; Section: Packing Methods.
- [3] These transparent plastic packages are extremely sensitive to reflow soldering conditions and must on no account be processed through more than one soldering cycle or subjected to infrared reflow soldering with peak temperature exceeding 217 °C ± 10 °C measured in the atmosphere of the reflow oven. The package body peak temperature must be kept as low as possible.

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- [4] These packages are not suitable for wave soldering. On versions with the heatsink on the bottom side, the solder cannot penetrate between the printed-circuit board and the heatsink. On versions with the heatsink on the top side, the solder might be deposited on the heatsink surface.
- [5] If wave soldering is considered, then the package must be placed at a 45° angle to the solder wave direction. The package footprint must incorporate solder thieves downstream and at the side corners.
- [6] Wave soldering is suitable for LQFP, QFP and TQFP packages with a pitch (e) larger than 0.8 mm; it is definitely not suitable for packages with a pitch (e) equal to or smaller than 0.65 mm.
- [7] Wave soldering is suitable for SSOP, TSSOP, VSO and VSSOP packages with a pitch (e) equal to or larger than 0.65 mm; it is definitely not suitable for packages with a pitch (e) equal to or smaller than 0.5 mm.
- [8] Image sensor packages in principle should not be soldered. They are mounted in sockets or delivered pre-mounted on flex foil. However, the image sensor package can be mounted by the client on a flex foil by using a hot bar soldering process. The appropriate soldering profile can be provided on request.
- [9] Hot bar soldering or manual soldering is suitable for PMFP packages.

### **15. Abbreviations**

Table 11:	Abbreviations
Acronym	Description
CDM	Charged Device Model
CMOS	Complementary Metal Oxide Silicon
ESD	ElectroStatic Discharge
GTL	Gunning Transceiver Logic
HBM	Human Body Model
LVTTL	Low Voltage Transistor-Transistor Logic
MM	Machine Model
PRR	Pulse Rate Repetition
TTL	Transistor-Transistor Logic

## 16. Revision history

Table 12: Revision history							
Document ID	Release date	Data sheet status	Change notice	Doc. number	Supersedes		
GTL2014_1	20050519	Product data sheet	-	9397 750 13534	-		

## 17. Data sheet status

Level	Data sheet status [1]	Product status <sup>[2]</sup> <sup>[3]</sup>	Definition
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
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[3] For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.

## **18. Definitions**

**Short-form specification** — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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